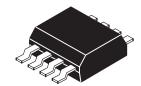
TPS1120, TPS1120Y DUAL P-CHANNEL ENHANCEMENT-MODE MOSFETS

SLVS080A - MARCH 1994 - REVISED AUGUST 1995

- Low $r_{DS(on)} \dots 0.18 \Omega$ at $V_{GS} = -10 \text{ V}$
- 3-V Compatible
- Requires No External V_{CC}
- TTL and CMOS Compatible Inputs
- $V_{GS(th)} = -1.5 \text{ V Max}$
- ESD Protection Up to 2 kV per MIL-STD-883C, Method 3015

D PACKAGE (TOP VIEW) 1SOURCE [1 8] 1DRAIN 1GATE [2 7] 1DRAIN 2SOURCE [3 6] 2DRAIN 2GATE [4 5] 2DRAIN



description

The TPS1120 incorporates two independent p-channel enhancement-mode MOSFETs that have been optimized, by means of the Texas Instruments LinBiCMOS™ process, for 3-V or 5-V

power distribution in battery-powered systems. With a maximum $V_{GS(th)}$ of -1.5 V and an I_{DSS} of only $0.5\,\mu\text{A}$, the TPS1120 is the ideal high-side switch for low-voltage portable battery-management systems, where maximizing battery life is a primary concern. Because portable equipment is potentially subject to electrostatic discharge (ESD), the MOSFETs have built-in circuitry for 2-kV ESD protection. End equipment for the TPS1120 includes notebook computers, personal digital assistants (PDAs), cellular telephones, bar-code scanners, and PCMCIA cards. For existing designs, the TPS1120D has a pinout common with other p-channel MOSFETs in small-outline integrated circuit SOIC packages.

The TPS1120 is characterized for an operating junction temperature range, T_J, from −40°C to 150°C.

AVAILABLE OPTIONS

| | PACKAGED DEVICEST | CHIP FORM |
|----------------|----------------------|-----------|
| ТЈ | SMALL OUTLINE (D) | (Y) |
| -40°C to 150°C | TPS1120D | TPS1120Y |

[†] The D package is available taped and reeled. Add an R suffix to device type (e.g., TPS1120DR). The chip form is tested at 25°C.

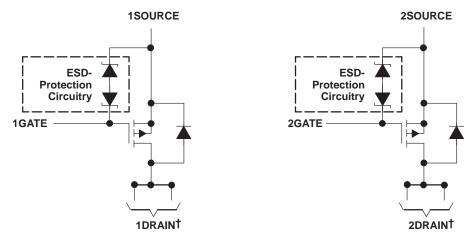


Caution. This device contains circuits to protect its inputs and outputs against damage due to high static voltages or electrostatic fields. These circuits have been qualified to protect this device against electrostatic discharges (ESD) of up to 2 kV according to MIL-STD-883C, Method 3015; however, it is advised that precautions be taken to avoid application of any voltage higher than maximum-rated voltages to these high-impedance circuits.

LinBiCMS is a trademark of Texas Instruments Incorporated.



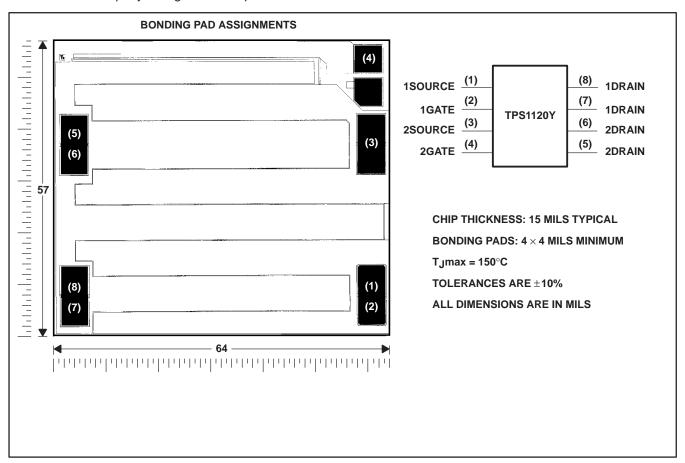
schematic



[†] For all applications, both drain pins for each device should be connected.

TPS1120Y chip information

This chip, when properly assembled, displays characteristics similar to the TPS1120C. Thermal compression or ultrasonic bonding may be used on the doped aluminum bonding pads. The chip may be mounted with conductive epoxy or a gold-silicon preform.



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absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

| Drain-to-source voltage, V _{DS} | | | -15 | V | |
|--|--------------------------|------------------------|-------|----|--|
| Gate-to-source voltage, VGS | 2 or –15 | V | | | |
| | V _{GS} = -2.7 V | T _A = 25°C | ±0.39 | | |
| Continuous drain current, each device (T _J = 150°C), I _D | VGS = -2.7 V | T _A = 125°C | ±0.21 | | |
| | V _{GS} = -3 V | T _A = 25°C | ±0.5 | A | |
| | VGS = -3 V | T _A = 125°C | ±0.25 | | |
| | V _{GS} = -4.5 V | T _A = 25°C | ±0.74 | | |
| | | T _A = 125°C | ±0.34 | | |
| | V _{GS} = -10 V | T _A = 25°C | ±1.17 | | |
| | | T _A = 125°C | ±0.53 | | |
| Pulse drain current, ID | | T _A = 25°C | ±7 | А | |
| Continuous source current (diode conduction), IS | | T _A = 25°C | -1 | А | |
| Continuous total power dissipation | ipation Rating | Table | | | |
| Storage temperature range, T _{Stg} | -55 to 150 | °C | | | |
| Operating junction temperature range, TJ | -40 to 150 | °C | | | |
| Operating free-air temperature range, TA | -40 to 125 | °C | | | |
| Lead temperature 1,6 mm (1/16 inch) from case for 10 second | onds | • | 260 | °C | |

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATING TABLE

| PAC | CKAGE | $T_A \le 25^{\circ}C$ POWER RATING | DERATING FACTOR [‡] ABOVE T _A = 25°C | T _A = 70°C POWER RATING | T _A = 85°C POWER RATING | T _A = 125°C POWER RATING |
|-----|-------|------------------------------------|--|---------------------------------------|---------------------------------------|--|
| | D | 840 mW | 6.71 mW/°C | 538 mW | 437 mW | 169 mW |

 $^{^{\}ddagger}$ Maximum values are calculated using a derating factor based on R_{θ JA} = 149°C/W for the package. These devices are mounted on an FR4 board with no special thermal considerations.



TPS1120, TPS1120Y DUAL P-CHANNEL ENHANCEMENT-MODE MOSFETS

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electrical characteristics at $T_J = 25^{\circ}C$ (unless otherwise noted)

static

| PARAMETER | | TEST COL | UDITIONS | 1 | | UNIT | |
|-----------|---|---------------------------|--------------------------|----|-------|-------|-------|
| | TANAMETEN | | TEST CONDITIONS | | | MAX | UNII |
| VGS(th) | Gate-to-source threshold voltage | $V_{DS} = V_{GS}$ | $I_D = -250 \mu\text{A}$ | -1 | -1.25 | -1.50 | V |
| V_{SD} | Source-to-drain voltage (diode forward voltage)† | $I_{S} = -1 A$, | V _{GS} = 0 V | | -0.9 | | V |
| IGSS | Reverse gate current, drain short circuited to source | $V_{DS} = 0 V$, | V _{GS} = -12 V | | | ±100 | nA |
| Inna | Zero-gate-voltage drain current | $V_{DS} = -12 \text{ V},$ | T _J = 25°C | | | -0.5 | |
| IDSS | Zero-gate-voltage drain current | $V_{GS} = 0 V$ | T _J = 125°C | | | -10 | μΑ |
| | | $V_{GS} = -10 \text{ V}$ | $I_D = -1.5 A$ | | 180 | | |
| r==() | Static drain-to-source on-state resistance† | $V_{GS} = -4.5 \text{ V}$ | $I_D = -0.5 A$ | | 291 | 400 | mΩ |
| rDS(on) | | $V_{GS} = -3 V$ | I= - 02A | | 476 | 700 | 11122 |
| | | $V_{GS} = -2.7 \text{ V}$ | $I_D = -0.2 \text{ A}$ | | 606 | 850 | |
| 9fs | Forward transconductance [†] | $V_{DS} = -10 \text{ V},$ | $I_{D} = -2 A$ | | 2.5 | | S |

[†] Pulse test: pulse width ≤ 300 μs, duty cycle ≤ 2%

static

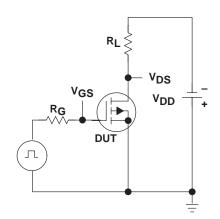
| | PARAMETER | TEST CO | TEST CONDITIONS | | | TPS1120Y | | |
|---------------------|---|---------------------------|--------------------------|-----|-------|----------|------------|--|
| | PARAMETER | | NDITIONS | MIN | TYP | MAX | UNIT | |
| V _{GS(th)} | Gate-to-source threshold voltage | $V_{DS} = V_{GS}$ | $I_D = -250 \mu\text{A}$ | | -1.25 | | V | |
| V _{SD} | Source-to-drain voltage (diode forward voltage)† | $I_{S} = -1 A$, | V _{GS} = 0 V | | -0.9 | | V | |
| | | $V_{GS} = -10 \text{ V}$ | $I_D = -1.5 A$ | | 180 | | | |
| | • · · · · · · · · · · · · · · · · · · · | $V_{GS} = -4.5 \text{ V}$ | $I_D = -0.5 A$ | | 291 | | ~ 0 | |
| rDS(on) | Static drain-to-source on-state resistance [†] | V _{GS} = −3 V | I- 02A | | 476 | | mΩ | |
| | | $V_{GS} = -2.7 \text{ V}$ | $I_D = -0.2 \text{ A}$ | | 606 | | | |
| 9fs | Forward transconductance† | $V_{DS} = -10 \text{ V},$ | $I_{D} = -2 A$ | | 2.5 | | S | |

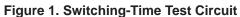
[†] Pulse test: pulse width ≤ 300 μs, duty cycle ≤ 2%

dynamic

| PARAMETER | | TEST CONDITIONS | | | TPS1120, TPS1120Y | | | LINUT |
|-----------------|---------------------------------------|---------------------------|---------------------|------------------|-------------------|------|-----|-------|
| | | | TEST CONDITIONS | | | | MAX | UNIT |
| Qg | Total gate charge | | | | | 5.45 | | |
| Qgs | Gate-to-source charge | $V_{DS} = -10 V$, | $V_{GS} = -10 V$, | $I_{D} = -1 A$ | | 0.87 | | nC |
| Q _{gd} | Gate-to-drain charge | 1 | | | | 1.4 | | |
| td(on) | Turn-on delay time | | | | | 4.5 | | ns |
| td(off) | Turn-off delay time | $V_{DD} = -10 \text{ V},$ | $R_L = 10 \Omega$, | $I_{D} = -1 A$, | | 13 | | ns |
| t _r | Rise time | $R_G = 6 \Omega$, | See Figures 1 and 2 | | | 10 | | |
| t _f | Fall time | | | | | 2 | | ns |
| trr(SD) | Source-to-drain reverse recovery time | I _F = 5.3 A, | di/dt = 100 A/μs | | | 16 | | |

PARAMETER MEASUREMENT INFORMATION





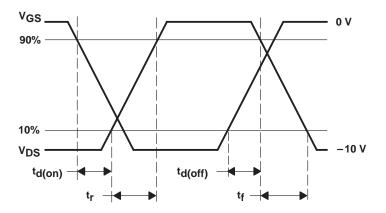
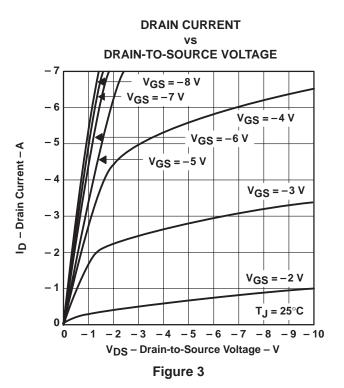


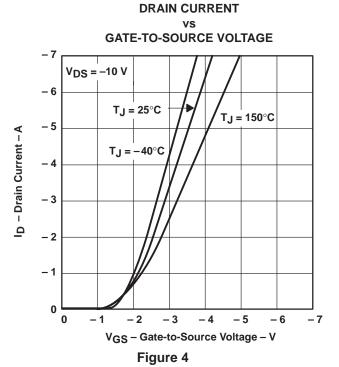
Figure 2. Switching-Time Waveforms

TYPICAL CHARACTERISTICS[†]

Table of Graphs

| | | FIGURE |
|---|----------------------------|--------|
| Drain current | vs Drain-to-source voltage | 3 |
| Drain current | vs Gate-to-source voltage | 4 |
| Static drain-to-source on-state resistance | vs Drain current | 5 |
| Capacitance | vs Drain-to-source voltage | 6 |
| Static drain-to-source on-state resistance (normalized) | vs Junction temperature | 7 |
| Source-to-drain diode current | vs Source-to-drain voltage | 8 |
| Static drain-to-source on-state resistance | vs Gate-to-source voltage | 9 |
| Gate-to-source threshold voltage | vs Junction temperature | 10 |
| Gate-to-source voltage | vs Gate charge | 11 |





[†] All characteristics data applies for each independent MOSFET incorporated on the TPS1120.

TYPICAL CHARACTERISTICS

STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

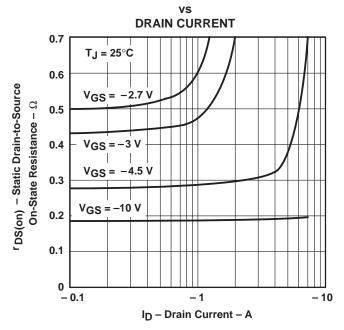
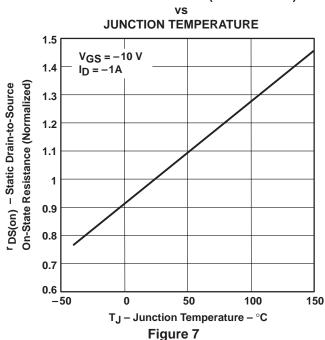
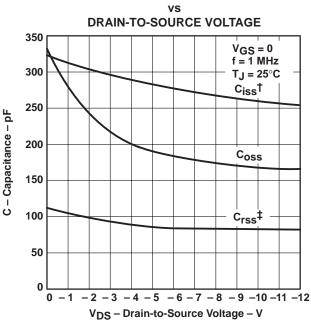


Figure 5

STATIC DRAIN-TO-SOURCE **ON-STATE RESISTANCE (NORMALIZED)**



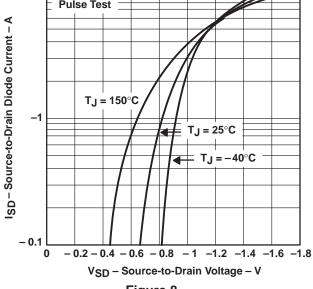
CAPACITANCE



 $\dagger C_{iss} = C_{gs} + C_{gd}, C_{ds(shorted)}$ $\ddagger C_{rss} = C_{gd}, C_{oss} = C_{ds} + \frac{C_{gs} C_{gd}}{C_{gs} + C_{gd}} \approx C_{ds} + C_{gd}$ Figure 6

SOURCE-TO-DRAIN DIODE CURRENT

SOURCE-TO-DRAIN VOLTAGE -10 Pulse Test



TYPICAL CHARACTERISTICS

STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

GATE-TO-SOURCE VOLTAGE 0.7 $I_D = -1 A$ ^rDS(on) - Static Drain-to-Source On-State T_J = 25°C 0.6 0.5 Resistance $-\Omega$ 0.4 0.3 0.2 0.1 0 - 9 - 13 - 15 - 1 V_{GS} - Gate-to-Source Voltage - V

Figure 9

GATE-TO-SOURCE THRESHOLD VOLTAGE

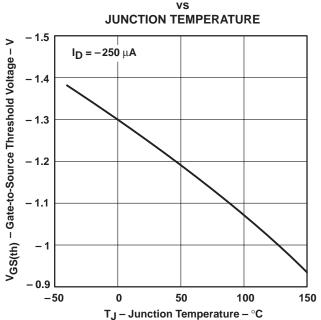


Figure 10

GATE-TO-SOURCE VOLTAGE vs GATE CHARGE

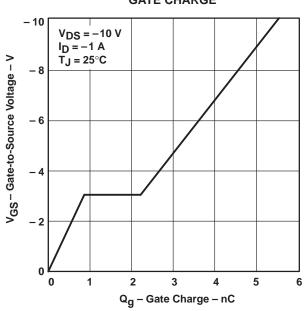
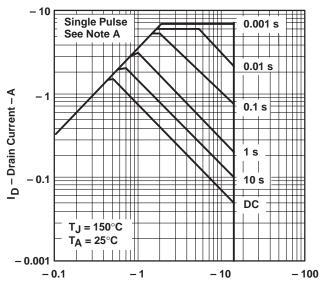


Figure 11

THERMAL INFORMATION

DRAIN CURRENT vs DRAIN-TO-SOURCE VOLTAGE



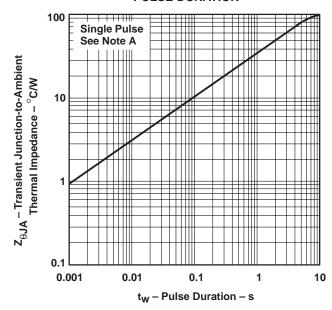
V_{DS} - Drain-to-Source Voltage - V

NOTE A: FR4-board-mounted only

Figure 12

TRANSIENT JUNCTION-TO-AMBIENT THERMAL IMPEDANCE

vs PULSE DURATION



NOTE A: FR4-board-mounted only

Figure 13

THERMAL INFORMATION

The profile of the heat sinks used for thermal measurements is shown in Figure 14. Board type is FR4 with 1-oz copper and 1-oz tin/lead (63/37) plate. Use of vias or through-holes to enhance thermal conduction was avoided.

Figure 15 shows a family of $R_{\theta JA}$ curves. The $R_{\theta JA}$ was obtained for various areas of heat sinks while subject to air flow. Power remained fixed at 0.25 W per device or 0.50 W per package. This testing was done at 25°C.

As Figure 14 illustrates, there are two separated heat sinks for each package. Each heat sink is coupled to the lead that is internally tied to a single MOSFET source and is half the total area, as shown in Figure 15. For example, if the total area shown in Figure 15 is 4 cm², each heat sink is 2 cm².

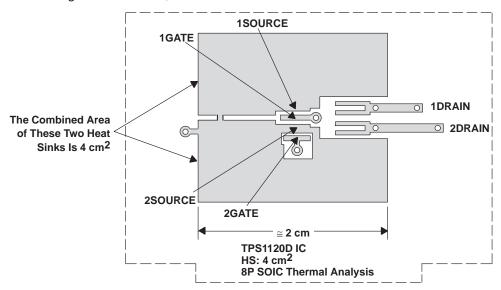
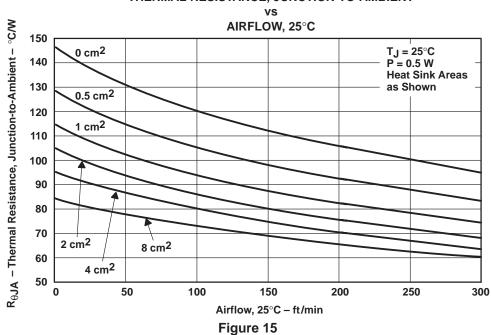


Figure 14. Profile of Heat Sinks

THERMAL RESISTANCE, JUNCTION-TO-AMBIENT





THERMAL INFORMATION

Figure 16 illustrates the thermally enhanced (SO) lead frame. Attaching the two MOSFET dies directly to the source terminals allows maximum heat transfer into a power plane.

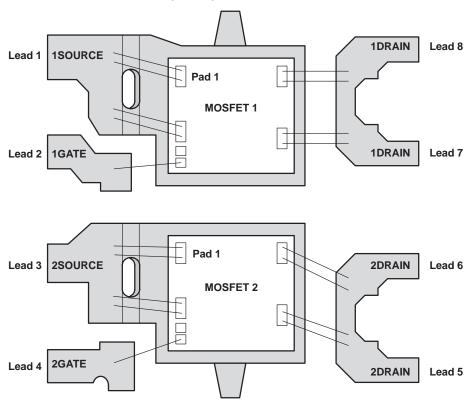


Figure 16. TPS1120 Dual MOSFET SO-8 Lead Frame

APPLICATION INFORMATION

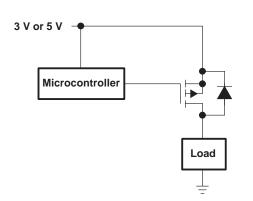


Figure 17. Notebook Load Management

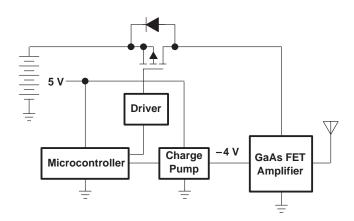


Figure 18. Cellular Phone Output Drive





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PACKAGING INFORMATION

| Orderable Device | Status ⁽¹⁾ | Package Type | Package Drawing | Pins I | Package Qty | e Eco Plan ⁽²⁾ | Lead/Ball Finish | MSL Peak Temp ⁽³⁾ |
|------------------|-----------------------|-----------------|--------------------|--------|----------------|---------------------------|------------------|------------------------------|
| TPS1120D | ACTIVE | SOIC | D | 8 | 75 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| TPS1120DR | ACTIVE | SOIC | D | 8 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| TPS1120DRG4 | ACTIVE | SOIC | D | 8 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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